

### **High-level functional test generation for microprocessor modules**

**Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes** Proceedings of 26th International Conference Mixed Design of Integrated Circuits and Systems : MIXDES 2019 : Rzeszów, Poland, June 27 - 29, 2019 2019 / p. 356-361 : ill <https://doi.org/10.23919/MIXDES.2019.8787131>

### **High-level test generation for processing elements in many-core systems**

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